Novel Methods for Dependable IoT Edge Applications

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Message from the Guest Editors

Dear Colleagues,

The Internet of things (IoT) promises to deliver a ubiquitous computing experience to users through massively interconnected computing and noncomputing devices, often referred to as cyber-physical devices (CPDs). The IoT edge network represents a myriad of CPDs that are interconnected to provide seamless computing solutions to various applications, including smart environment control and intelligent system management.

CPDs, however, present security concerns, as some of them are unworthy, noncomputing devices that are given the cybercommunication capacity to support the rapid expansion of IoT applications. Subsequently, IoT edge applications are often considered nondependable in terms of their security and quality assurance.

This Special Issue aims to bring together researchers from both academia and industry in the application of novel methods for dependable IoT edge network applications. The main topics of this Special Issue include, but are not limited to, the following:

- Data analytics middleware for edge computing.
- Edge-based intelligent analytics.
- Edge-node-driven data analytics.

Special Issue

Editor-in-Chief

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Message from the Editor-in-Chief

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